



Accredited Laboratory

A2LA has accredited

FISCHER TECHNOLOGY, INC. USA

Windsor, CT

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCCL Z540-1-1994 and R205 – Specific Requirements: Calibration Laboratory Accreditation Program. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



Presented this 9th day of August 2023.

A blue ink signature of Mr. Trace McInturff, written over a horizontal line.

Mr. Trace McInturff, Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 3576.01
Valid to August 31, 2025

For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017
& ANSI/NCSL Z540-1-1994

FISCHER TECHNOLOGY, INC.
750 Marshall Phelps Road
Windsor, CT 06095
George Hoag Phone: 860 683 0781

CALIBRATION

Valid To: August 31, 2025

Certificate Number: 3576.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations¹:

I. Dimensional

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Coating Thickness ³ – Measuring Equipment (µin – Microinch)	Up to 5 µin thin layer 5 to 2800 µin	11 % 3.5 %	ASTM B568 x-ray fluorescence
	Up to 900 µin alloy thickness Up to 99.9 % alloy composition	5.2 % 3.5 %	ASTM B568 x-ray fluorescence
	Up to 1 mils (1 to 1200) mils	1.7 % 0.8 %	Eddy current & magnetic induction, ASTM B244, E376
	Up to 5 mils (5 to 30) mils	6.0 % 5.0 %	ASTM B567 beta backscatter
	Up to 3000 µin	5.0 %	ASTM B504 coulometric method
	Up to 1 mils	7.0 %	Plated Cu over epoxy ASTM E376 eddy current

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Coating Thickness Standards (µin – Microinch)	Up to 5 µin thin layer (5 to 2800) µin	11 % 3.5 %	ASTM B568 X-ray fluorescence
	Up to 900 µin alloy thickness Up to 99.9 % alloy composition	5.2 % 3.5 %	ASTM B568 X-ray fluorescence
	Up to 2 mils (2 to 1200) mils	1.7 % 0.8 %	Digital indicator/ micrometer
	Up to 5 mils (5 to 30) mils	6.0 % 5.0 %	ASTM B567 - 14 beta backscatter
	Up to 3000 µin	5.0 %	ASTM B504 coulometric method
	Up to 1 mils	4.0 %	Plated Cu over epoxy ASTM E376 eddy current

II. Electrical – DC/Low Frequency

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Electrical Conductivity – Measuring Equipment (% IACS – International Annealed Copper Standard)	Up to 16 % IACS	2.0 %	ASTM E1004-17 electrical conductivity by eddy current
	(> 16 to 35) % IACS	1.0 %	
	(> 35 to 62) % IACS	0.35 %	
	(> 62 to 104) % IACS	1.0 %	
Electrical Conductivity Standards (% IACS – International Annealed Copper Standard)	Up to 16 % IACS	2.0 %	ASTM E1004-17 electrical conductivity by eddy current
	(> 16 to 35) % IACS	1.0 %	
	(> 35 to 62) % IACS	0.35 %	
	(> 62 to 104) % IACS	1.0 %	

III. Magnetic Quantities

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Ferrite Content ³ – Measuring Equipment (FN – Ferrite Number)	(0 to 6) FN (6 to 140) FN	0.6 FN 10 %	ASTM A799 / A799M ferrite content by magnetic induction
Ferrite Content Standards (FN – Ferrite Number)	(0 to 6) FN (6 to 140) FN	0.6 FN 10 %	ASTM A799 / A799M ferrite content by magnetic induction

IV. Mechanical

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Indirect Verification of Instrumented Indentation Hardness Testers (Martens) (HM – Martens Hardness)	4000 HM	4.0 %	Reference block and certified indenter

¹ This laboratory offers commercial calibration service and field calibration service.

² Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC Uncertainty due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

³ Field calibration service is available for this calibration. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC Uncertainty found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC Uncertainty.

⁴ In the statement of CMC, the value is defined as the percentage of reading, unless otherwise noted.